

[METHOD OF FABRICATING A FLASH MEMORY CELL]

Abstract of Disclosure

A simplified flash memory fabrication process is disclosed. The method includes the following steps: 1) forming a stacked layer on a substrate in the channel region, and the stacked layer is a polysilicon layer and a sacrificial layer formed atop the polysilicon layer; 2) depositing a dielectric layer to cover the channel region and the bit line region; 3) performing an isotropic dry etching process to etch away a predetermined thickness of the dielectric layer to expose a portion of the sacrificial layer, and at the same time, dividing the dielectric layer into a first portion dielectric layer positioned atop the sacrificial layer and a second portion dielectric layer that is not connected with the first portion dielectric layer; and 4) completely removing the sacrificial layer and the first portion dielectric layer.

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